

Form PTO-1449

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Applicant: Ryuzo Iga et al.

Confirmation No.: 9935

Serial No.: 10/577,626

Att'y Docket No.: 14321.84

Filing Date: April 28, 2006

Art Unit: 2828

For: SEMICONDUCTOR OPTICAL DEVICE AND A METHOD OF FABRICATING THE SAME

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
____ 1	5,470,785	11/28/1995	Kondo
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Foreign Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
____ 6	61-180493	08/13/1986	Japan	Partial
____ 7	3-53582	03/07/1991	Japan	Partial
____ 8	05-021891	01/29/1993	Japan	No
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Examiner: /Patrick Stafford/

Date Considered: 07/08/2008

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Sheet 2 of 2

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Other Documents

(including author, title, pertinent pages, etc.)

Examiner

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- _____ 21 Ryuzo Iga et al., *Ruthenium-Doped InP Buried 1.3 μm DFB Lasers on a P-Type Substrate*, 2004 International Conference on Indium Phosphide and Related Materials, Conference Proceedings, 16th IPRM, Kagoshima, Japan, May 31-June 4, 2004, pp. 742-745.
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References Cited by Applicants

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Examiners will consider all citations submitted in conformance with 37 C.F.R. § 1.98 and MPEP Sec. 609 and place their initials adjacent the citations in the spaces provided on this form. Examiners will also initial citations not in conformance with the guidelines which may have been considered. A reference may be considered by the Examiner for any reason whether or not the citation is in full conformance with the guidelines. A line will be drawn through a citation if it is not in conformance with the guidelines AND has not been considered. A copy of the submitted form, as reviewed by the Examiner, will be returned to the applicant with the next communication. The original of the form will be entered into the application file.

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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Date Considered: 07/08/2008

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